

#### Structure factor

Ch 14.3 Oxford Basics

Experiments measure the intensity

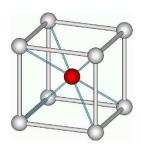
Consider some structure factors

$$S_{(hkl)} = \sum f_j e^{2\pi i(hx_j + ky_j + lz_j)}$$

 $f_i$  form factor

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Example 1: Caesium Chloride



Can be described as a simple cubic with a basis given by

Basis for CsCl				
Cs	Position=	[0, 0, 0]		
Cl	Position=	[a/2, a/2, a/2]		

Recall – we found that we will see diffraction spots for all h,k,l but a stronger intensity when the h+k+l are even as compared to h+k+l odd.

 $I_{(hkl)} \propto |S_{(hkl)}|^2$ 

$$S_{(hkl)} = f_{Cs} + f_{Cl} e^{2\pi i (h,k,l) \cdot [1/2,1/2,1/2]}$$
$$= f_{Cs} + f_{Cl} (-1)^{h+k+l}$$

#### Systematic absences or selection rules

Example 2: Caesium bcc

Consider pure Cs – simply replace the Cl in CsCl with another Cs atom. Simple cubic lattice with basis: (for neutron scattering)

Cs

Basis for Cs bcc
Position= 
$$[0,0,0]$$
Position=  $[a/2,a/2,a/2]$ 
 $S(\mathbf{G}) \sim \sum_{\text{atom } j \text{ in unit cell}} b_j \ e^{i\mathbf{G} \cdot \mathbf{x_j}}$ 
 $\mathbf{a}_i \cdot \mathbf{b}_j = 2\pi \delta_{ij}$ 
 $\mathbf{G} = h \mathbf{b_1} + k \mathbf{b_2} + l \mathbf{b_3}$ 

$$S_{(hkl)} = f_{Cs} + f_{Cs} e^{2\pi i (h,k,l) \cdot [1/2,1/2,1/2]}$$
  
=  $f_{Cs} [1 + (-1)^{h+k+l}]$ 

Scattering intensity vanishes for h+k+l being any odd integer!

For h+k+l being even, get structure factor =  $2f_{Cs}$ 

So if your unknown material is bcc, you can identify it as such due to characteristic missing diffraction spots.

#### Systematic absences or selection rules

Example 3: Copper fcc

Simple cubic with a basis: [0,0,0], [1/2,1/2,0], [1/2,0,1/2], and [0,1/2,1/2]

$$S_{(hkl)} = f_{Cu} \left[ 1 + e^{i\pi(h+k)} + e^{i\pi(h+l)} + e^{i\pi(k+l)} \right]$$

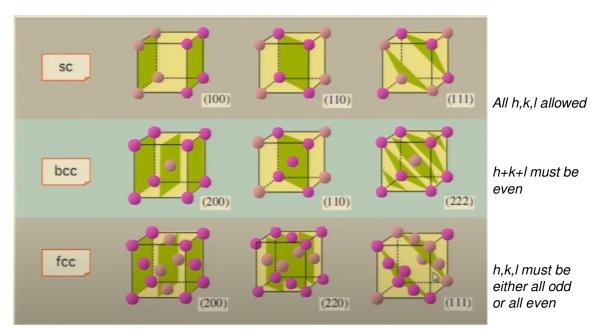
This expression vanishes unless *h*, *k* and *l* are either all odd or all even.

Systematic Absences of Scattering					
Simple Cubic	all $h, k, l$ allowed				
bcc	h + k + l must be even				
fcc	h,k,l must be all odd or all even				

"selection rules"

So the observed diffraction spots will satisfy these selection rules for a given structure.

#### Geometric interpretation of selection rules



This is because we are using the conventional cubic unit cell with lattice vectors **a** which are not the primitive lattice vectors for bcc and fcc structures. But it is more convenient to work with orthogonal axes.

#### Systematic absences

Example 4: Zinc Sulfide = fcc with a basis:

Zincblende structure – fcc with a basis: Zn at [0,0,0], S at [1/4,1/4,1/4]. Consider it as a simple cubic lattice with basis of 8 atoms in the conv. unit cell:

			Basis for ZnS			
Zn	Positions=	[0,0,0],	[1/2, 1/2, 0],	[1/2, 0, 1/2],	and	[0, 1/2, 1/2]
S	Positions=	[1/4, 1/4, 1/4],	[3/4, 3/4, 1/4],	[3/4, 1/4, 3/4],	and	[1/4, 3/4, 3/4]

$$S_{(hkl)} = f_{Zn} \left[ 1 + e^{2\pi i(hkl) \cdot [1/2,1/2,0]} + \dots \right] + \dots$$

$$f_S \left[ e^{2\pi i(hkl) \cdot [1/4,1/4,1/4]} + e^{2\pi i(hkl) \cdot [3/4,3/4,1/4]} + \dots \right]$$

$$S_{(hkl)} = \left[ 1 + e^{i\pi(h+k)} + e^{i\pi(h+l)} + e^{i\pi(k+l)} \right] \left[ f_{Zn} + f_S e^{i(\pi/2)(h+k+l)} \right]$$

Same term we found for the fcc crystal

Term associated with ZnS

In general:

$$S_{(hkl)} = S_{(hkl)}^{Lattice} \times S_{(hkl)}^{basis}$$

(check the above expression is true as exercise)

#### Scattering intensity – powder diffraction

Powder diffraction: wave scattering on a sample that is not single crystalline, but is powdered – wave can scatter from many small crystals which may be oriented in any possible direction.

Recall that there are equivalent families of planes, e.g. six (for simple cubic)

$$(0\bar{1}0), (00\bar{1})(100)(010), (001), (\bar{1}00) = \{100\}$$

eight:

$$(111), (11\bar{1}), (1\bar{1}1), (1\bar{1}1), (\bar{1}11), (\bar{1}11), (\bar{1}11), (\bar{1}11) = \{111\}$$

This is called the multiplicity factor, thus more accurately we should write the measured intensity:

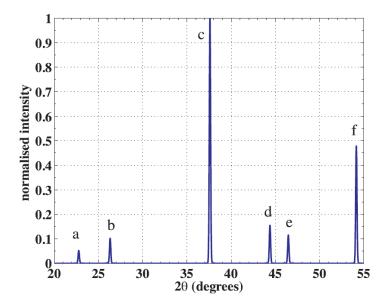
$$I_{\{hkl\}} \propto M_{\{hkl\}} |S_{\{hkl\}}|^2$$

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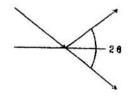
#### Neutron scattering: powder diffraction from PrO<sub>2</sub>

Ch. 14.3 Oxford Basics

Given experimental results see how to determine structure

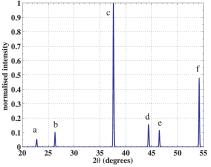


See deflection by 20:



Collate a table, reading off the deflection angles, and corresponding distances and possible relationship to Miller indices

$$d_{(hkl)} = \frac{\lambda}{2\sin\theta} = \frac{a}{\sqrt{h^2 + k^2 + l^2}}$$



$$\lambda = .123 \text{ nm}$$

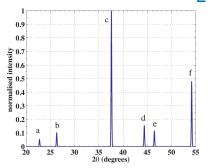
pea	k 2θ	$d = \lambda/(2\sin\theta)$	$d_a^2/d^2$	$3d_a^2/d^2$	$N = h^2 + k^2 + l^2$
a	22.7°	$\frac{a - \lambda/(2 \sin \theta)}{0.313 \text{ nm}}$	1	$\frac{3a_a/a}{3}$	$\frac{1}{3}$
l b	26.3°	0.270 nm	1.33	3.99	4
c	37.7°	$0.190~\mathrm{nm}$	2.69	8.07	8
d	44.3°	$0.163~\mathrm{nm}$	3.67	11.01	11
e	46.2°	$0.157~\mathrm{nm}$	3.97	11.91	12
f	$54.2^{\circ}$	$0.135 \; \mathrm{nm}$	5.35	16.05	16

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#### Working

Calculate the corresponding lattice constant in last column, and average value, find:

$$a = .541 \pm .002 \text{ nm}$$



#### Find which h,k,l give the N

				•	
peak	$2\theta$	$d = \lambda/(2\sin\theta)$	$N = h^2 + k^2 + l^2$	$\{hkl\}$	$a = d\sqrt{h^2 + k^2 + l^2}$
$\mathbf{a}$	$22.7^{\circ}$	$0.313 \; { m nm}$	3	111	.542  nm
b	$26.3^{\circ}$	$0.270 \; \mathrm{nm}$	4	200	$.540 \mathrm{\ nm}$
$\mathbf{c}$	$37.7^{\circ}$	$0.190~\mathrm{nm}$	8	220	.537  nm
$^{\mathrm{d}}$	$44.3^{\circ}$	$0.163~\mathrm{nm}$	11	311	$.541~\mathrm{nm}$
$\mathbf{e}$	$46.2^{\circ}$	$0.157~\mathrm{nm}$	12	222	$.544~\mathrm{nm}$
f	$54.2^{\circ}$	$0.135 \mathrm{\ nm}$	16	400	.540  nm

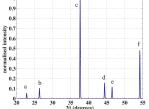
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# Neutron scattering: powder diffraction from PrO<sub>2</sub>

		0 1				_
$N = h^{2} + k^{2} + l^{2}$ 3 4 8 11 12	{hkl} 111 200 220 311 222	ls it cubic, bcc, fcc? Consider the known selection rules  Lattice Pla	G: 1 G 1:	atic Absences of S all $h, k, l$ allow $h + k + l$ must $h, k, l$ must be	ed be even	
16	400   {hkl	$N = h^2 + k^2 + l^2$	Multiplicity	cubic	bcc	fcc
we found	100 110 111		6 12 8	√ √ ./	✓	./
	200 210	4	$\phantom{aaaaaaaaaaaaaaaaaaaaaaaaaaaaaaaaaaa$	<b>√</b> ✓	✓	<b>√</b>
	211 220 221		12 24	√ √	<b>√</b>	✓
	300 310	9	6 24	<b>√</b> ✓	$\checkmark$	
12	311 222	11 12	24 8	✓ ✓	✓	<b>√</b> ✓

We can also analyse the measured intensities

$$I_{\{hkl\}} \propto M_{\{hkl\}} |S_{\{hkl\}}|^2$$



Calculate the structure factor.

PrO<sub>2</sub>: the Pr atoms form the fcc lattice and O atoms fill gaps, the basis is:

(Pr) at 
$$[0,0,0]$$
  
(O) at  $[1/4,1/4,1/4]$  and  $[1/4,1/4,3/4]$ 



$$S_{(hkl)} = \left[1 + e^{i\pi(h+k)} + e^{i\pi(h+l)} + e^{i\pi(k+l)}\right] \left[b_{Pr} + b_O\left(e^{i(\pi/2)(h+k+l)} + e^{i(\pi/2)(h+k+3l)}\right)\right]$$
Structure factor for the fee lettice

Structure factor for the fcc lattice, gives 4 for every allowed scattering point

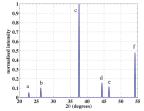
Structure factor for the basis

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#### Neutron scattering: powder diffraction from

## PrO<sub>2</sub>

$$I_{\{hkl\}} \propto M_{\{hkl\}} |S_{\{hkl\}}|^2$$

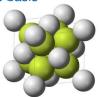


$$S_{(hkl)} = \left[1 + e^{i\pi(h+k)} + e^{i\pi(h+l)} + e^{i\pi(k+l)}\right] \left[b_{Pr} + b_O\left(e^{i(\pi/2)(h+k+l)} + e^{i(\pi/2)(h+k+3l)}\right)\right]$$

Structure factor for the fcc lattice

Structure factor for the basis

First term will be zero unless h,k,l are either all odd or all even (gives value of 4 for each allowed h,k,l). Can write:



$$I_{\{hkl\}} = CM_{\{hkl\}} \left| b_{Pr} + b_O \left( e^{i(\pi/2)(h+k+l)} + e^{i(\pi/2)(h+k+3l)} \right) \right|^2$$

C is a constant (including the factor of  $4^2$  for the fcc structure factor)

$$I_{\{hkl\}} = CM_{\{hkl\}} \left| b_{Pr} + b_O \left( e^{i(\pi/2)(h+k+l)} + e^{i(\pi/2)(h+k+3l)} \right) \right|^2$$

#### Can create a table, predicted intensity and measured

	Scattering Intensity						
p	$\operatorname{eak}$	$\{hkl\}$	$I_{\{hkl\}}/C \propto M S ^2$	Measured Intensity			
	a	111	$8 b_{Pr}^2$	0.05			
	b	200	$6[b_{Pr}-2b_{O}]^{2}$	0.1			
	c	220	$12[b_{Pr}+2b_{O}]^{2}$	1.0			
	d	311	$24  b_{Pr}^2$	0.15			
	e	222	$8[b_{Pr}-2b_{O}]^{2}$	0.13			
	f	400	$6[b_{Pr}+2b_{O}]^{2}$	0.5			

From analytic expressions, predict 
$$I_d=3I_a$$
  $I_c=2I_f$   $I_e=\frac{4}{3}I_b$  Consistent with measured intensities

$$\frac{I_c}{I_a} = \frac{12[b_{Pr} + 2b_O]^2}{8b_{Pr}^2} = 20$$

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#### Neutron scattering: powder diffraction from PrO<sub>2</sub>

Can solve

$$\frac{I_c}{I_a} = \frac{12[b_{Pr} + 2b_O]^2}{8b_{Pr}^2} = 20$$



to find 
$$b_{Pr}/b_O \approx .75$$

Have used the neutron data to experimentally determine the ratio of the nuclear scattering lengths.

# Neutron scattering: powder diffraction from

PrO<sub>2</sub>

Further we can calculate

$$\frac{I_b}{I_a} = \frac{6[b_{Pr} - 2b_O]^2}{8b_{Pr}^2} = 2$$

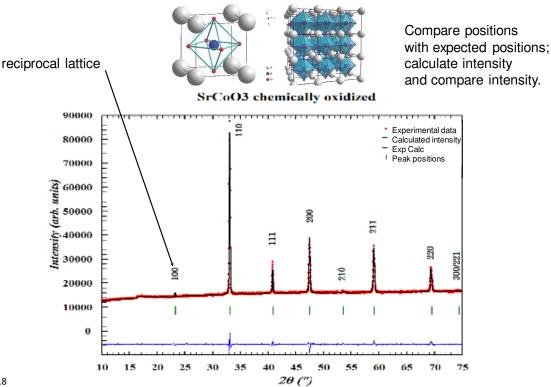
which we can solve to give

$$b_{Pr} = .76 \, b_O$$
 or  $b_{Pr} = -3.1 \, b_O$ 

Former is compatible with what was obtained earlier (latter is not).

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#### Powder diffraction

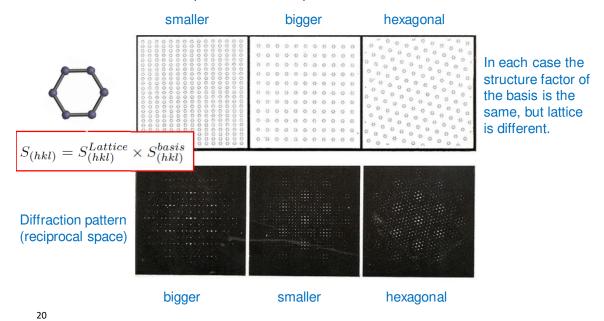


### X-ray/neutron diffraction in practice

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#### Example of "benzene crystal" in 2D

A crystal is a convolution of a basis with a Bravais lattice, therefore the Fourier transform is a product of a reciprocal Bravais lattice and the transform of the basis (structure factor).



#### Shape function

The Fourier transform of a direct lattice is only a lattice of points if the direct lattice is infinite. A finite lattice is an infinite lattice multiplied by a 'shape function' which is unity inside the sample and zero elsewhere ('top hat function').

The Fourier transform of the finite lattice is the convolution of the infinite lattice and the transform of the shape function.

This means that each reciprocal lattice point is broadened or **smeared out**.

# Small crystals therefore do not have sharp diffraction peaks.

The converse effect is seen when the diffraction pattern is transformed back to give the object.

This shows how finite collection of data in a diffraction experiment limits the information recoverable.



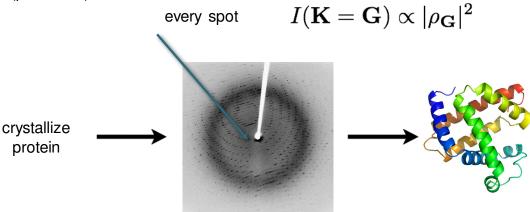


Optical Transforms Taylor and Lipson

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#### Advanced X-ray diffraction

- The position of the spots gives information about the reciprocal lattice and thus the Bravais lattice.
- An intensity analysis can give information about the basis.
- Even the structure of a very complicated basis can be determined (proteins...)



Why so many spots for a protein? - real space is big, so reciprocal space tiny!

#### Advanced X-ray sources: synchrotron radiation

SPring-8, Japan

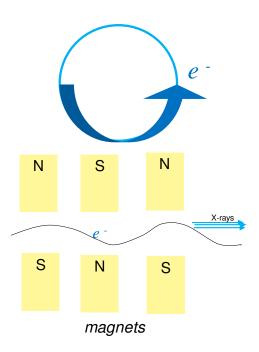
Australian synchrotron



- A highly collimated and monochromatic beam is needed for protein crystallography.
- This can only be provided by a synchrotron radiation source.

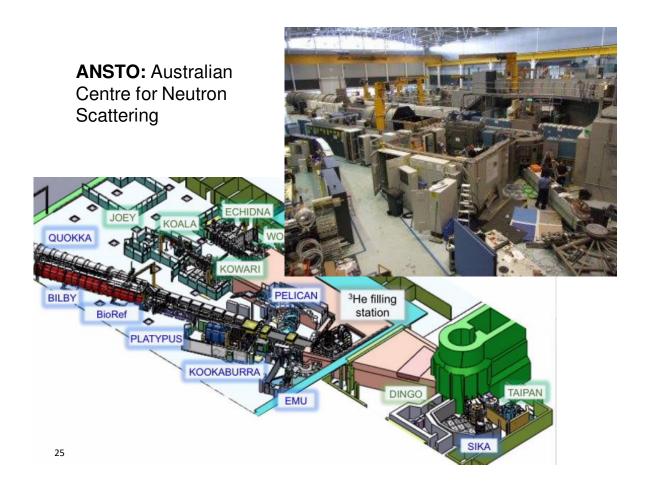
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#### Producing X-rays at a synchrotron



Electrons accelerated around the ring at energy in the GeV range. To get X-rays, electron beam is passed through a series of magnets, called an "undulator" or a "wiggler" These accelerate the electrons so that they emit radiation that is highly collimated and well defined in frequency.

If want to specify the frequency (wavelength) more precisely, then the X-rays are diffracted off a known crystal that will pick out particular wavelengths, called a "diffraction grating".



Diamond synchrotron light source



Rutherford-Appleton Lab in Oxfordshire UK

#### Producing neutrons

#### Nuclear reactor Uranium-235

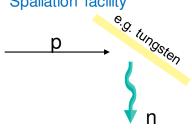
Fast neutron neutron Moderator (ex. water) A nuclear reactor is driven by the splitting of atoms, a process called fission, where a particle (a 'neutron') is fired at an atom. which then fissions into two smaller atoms and some additional neutrons

When a slow neutron collides with a fissile material like Uranium-235, it produces fast neutrons. The moderator will then slow these fast neutrons, and produce more slow neutrons to continue the nuclear chain reaction. When this process is repeated the fissile events are doubled each time

Protons are accelerated at GeV energies and hit a target knocking out neutrons.

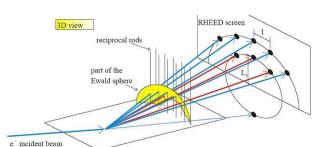
A modern facility could produce about 10<sup>16</sup> neutrons/(s cm<sup>2</sup>) (the flux or brightness).

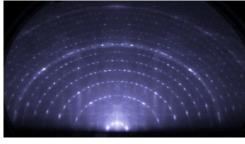
Spallation facility



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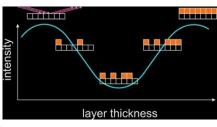
#### Reflection High Energy Electron Diffraction (RHEED)

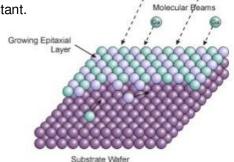




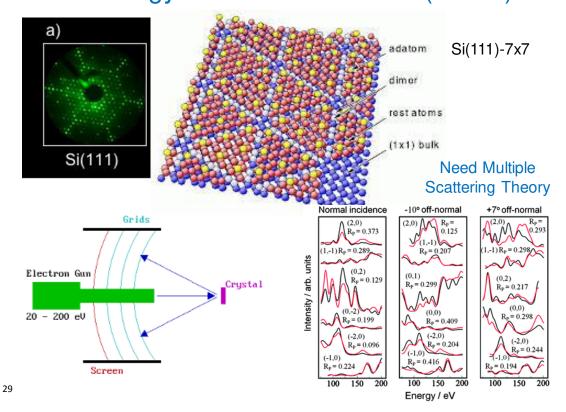
4-50 keV electrons "grazing incidence", angle 1-4°

Used to characterize the surface of a crystalline material, e.g., growing GaAs - can monitor growth in situ and measure how many lavers you have (thickness) and quality of surface (how rough it is), orientation of crystal, lattice constant.





# Low Energy Electron Diffraction (LEED)



End